

P06 LTE B25_QPSK20M_Right Cheek_Ch26340_1RB_OS50

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, -	CHEEK, 0.00	Band 25	LTE-FDD, -	1880.000, 26340	7.97	1.36	38.4

Hardware Setup

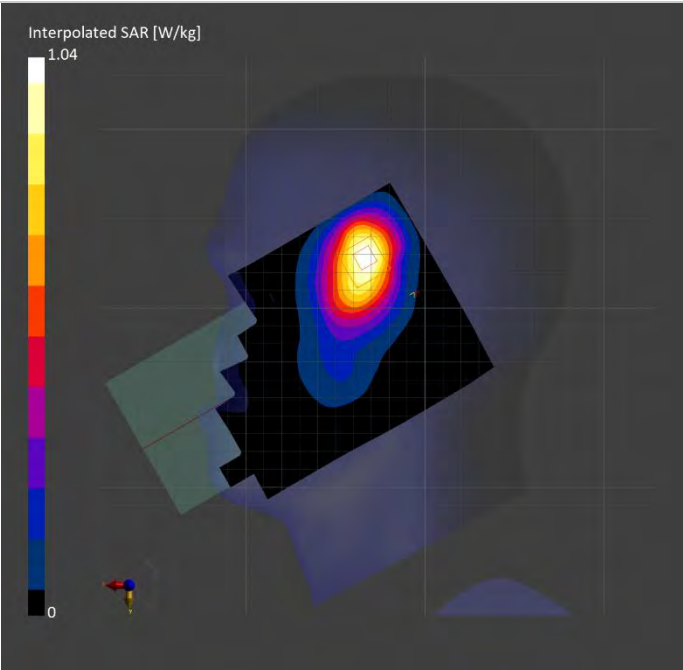
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL1950-2025-04-29	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-29	2025-04-29
psSAR1g [W/kg]	0.850	0.871
psSAR10g [W/kg]	0.491	0.510
Power Drift [dB]	-0.05	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.7
Dist 3dB Peak [mm]		13.5



P07 LTE B26_QPSK15M_Left Cheek_Ch26965_1RB_OS74

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, -	CHEEK, 0.00	Band 26	LTE-FDD, -	841.500, 26965	9.47	0.902	42.9

Hardware Setup

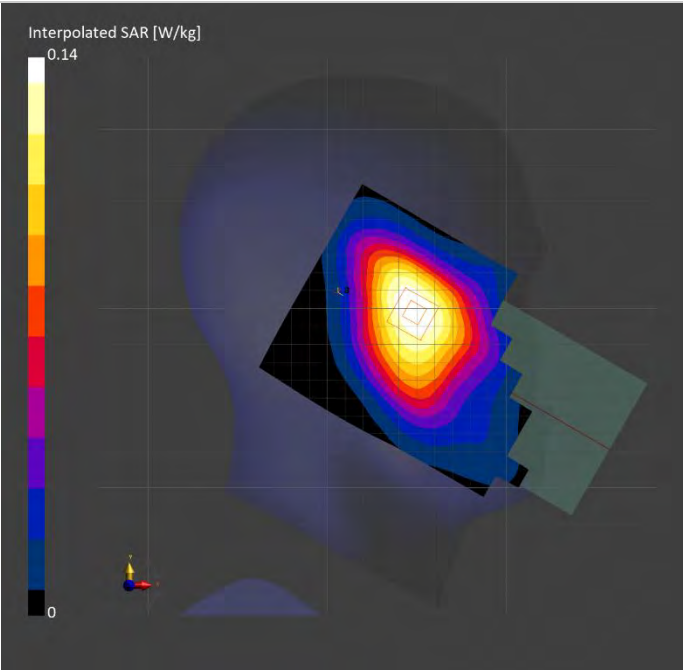
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL835-2025-04-13	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-13	2025-04-13
psSAR1g [W/kg]	0.122	0.128
psSAR10g [W/kg]	0.085	0.102
Power Drift [dB]	-0.04	-0.05
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		91.2
Dist 3dB Peak [mm]		> 15.0



P08 LTE B30_QPSK10M_Right Cheek_Ch27710_25RB_OS12

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, -	CHEEK, 0.00	Band 30	LTE-FDD, -	2310.000, 27710	7.71	1.74	40.4

Hardware Setup

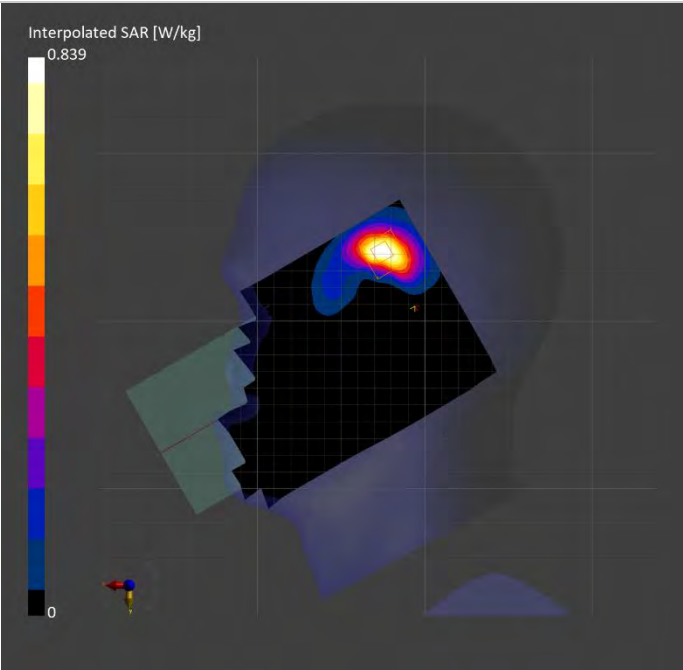
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL2300-2025-04-14	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 220.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-14	2025-04-14
psSAR1g [W/kg]	0.644	0.671
psSAR10g [W/kg]	0.317	0.332
Power Drift [dB]	0.01	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.0
Dist 3dB Peak [mm]		8.6



P09 LTE B38_QPSK20M_Left Cheek_Ch37850_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, -	CHEEK, 0.00	Band 38	LTE-TDD, -	2580.000, 37850	7.31	1.92	40.1

Hardware Setup

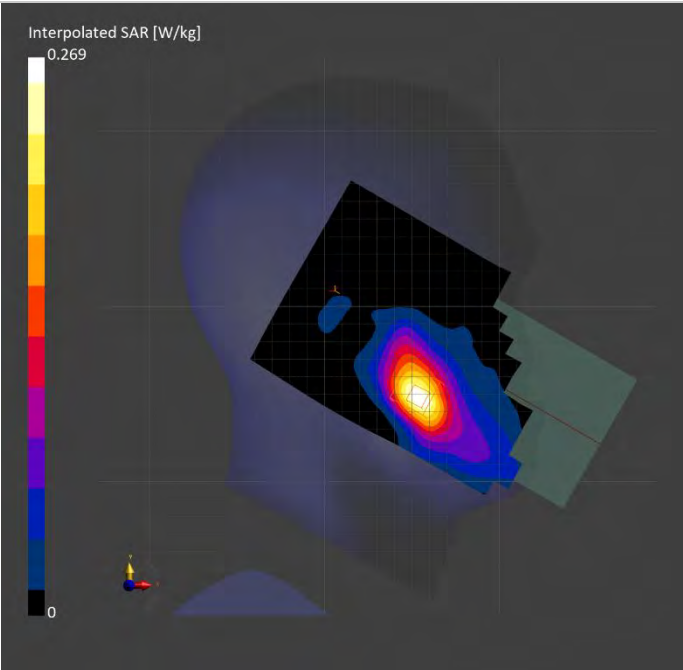
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL2550-2025-04-16	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 220.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-16	2025-04-16
psSAR1g [W/kg]	0.208	0.215
psSAR10g [W/kg]	0.106	0.116
Power Drift [dB]	-0.04	-0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		84.9
Dist 3dB Peak [mm]		10.8



P10 LTE B41_QPSK20M_Right Cheek_Ch41055_50RB_OS25

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, -	CHEEK, 0.00	Band 41	LTE-TDD, -	2636.500, 41055	7.31	1.94	38.2

Hardware Setup

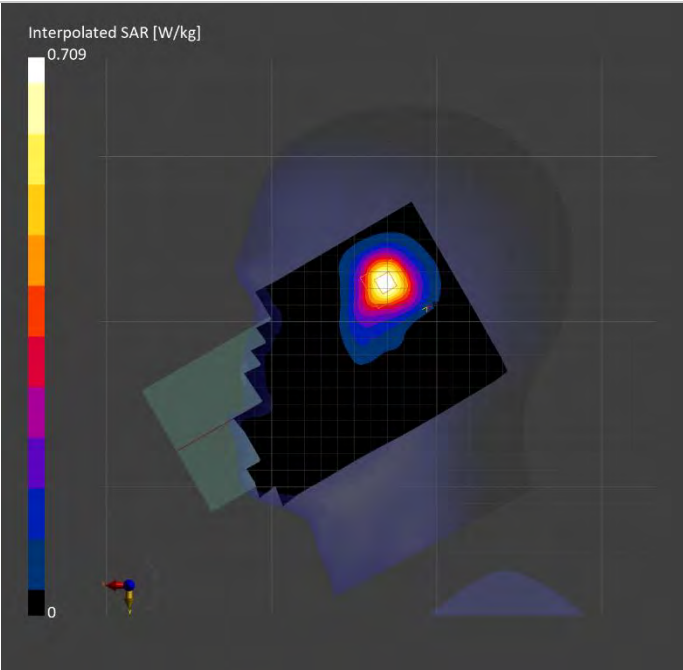
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL2550-2025-04-18	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 220.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-18	2025-04-18
psSAR1g [W/kg]	0.528	0.408
psSAR10g [W/kg]	0.260	0.268
Power Drift [dB]	-0.08	-0.08
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		82.0
Dist 3dB Peak [mm]		12.4



P11 LTE B42_QPSK20M_Right Cheek_Ch42990_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, -	CHEEK, 0.00	Band 42	LTE-TDD, -	3540.000, 42990	6.71	2.82	37.6

Hardware Setup

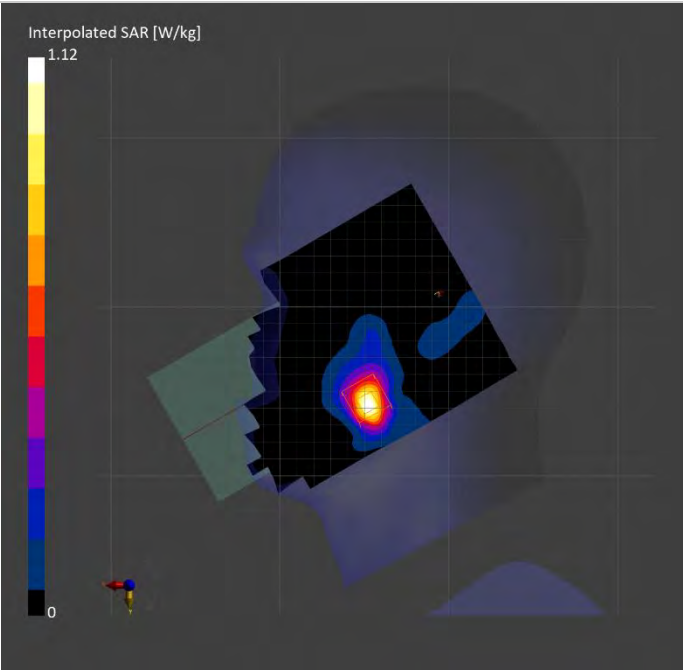
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL3500-2025-05-11	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	128.0 x 208.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	8.0 x 8.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-11	2025-05-11
psSAR1g [W/kg]	0.786	0.746
psSAR10g [W/kg]	0.315	0.291
Power Drift [dB]	-0.05	-0.14
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		77.4
Dist 3dB Peak [mm]		7.9



P12 LTE B43_QPSK20M_Right Cheek_Ch44490_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, -	CHEEK, 0.00	Band 43	LTE-TDD, -	3690.000, 44490	6.50	3.04	37.4

Hardware Setup

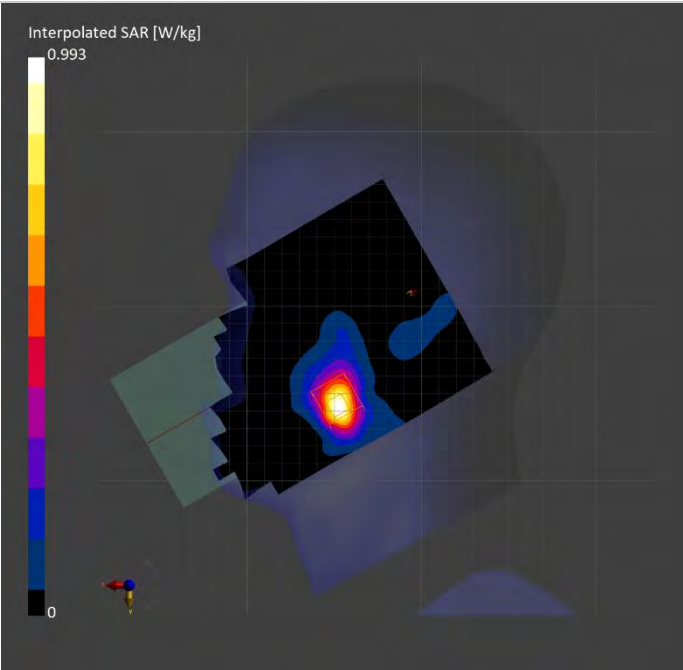
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL3700-2025-05-12	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	128.0 x 208.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	8.0 x 8.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-12	2025-05-12
psSAR1g [W/kg]	0.702	0.691
psSAR10g [W/kg]	0.287	0.277
Power Drift [dB]	-0.04	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		79.1
Dist 3dB Peak [mm]		8.9



P13 LTE B48_QPSK20M_Right Cheek_Ch56640_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, -	CHEEK, 0.00	Band 48	LTE-TDD, -	3690.000, 56640	6.50	3.05	37.5

Hardware Setup

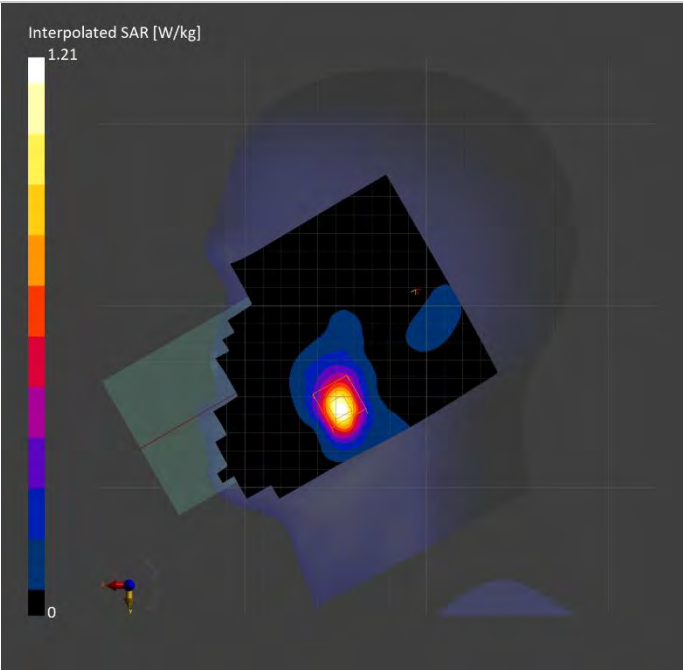
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL3700-2025-05-13	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	128.0 x 208.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	8.0 x 8.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-13	2025-05-13
psSAR1g [W/kg]	0.848	0.869
psSAR10g [W/kg]	0.338	0.346
Power Drift [dB]	0.05	-0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		79.5
Dist 3dB Peak [mm]		8.6



P14 LTE B66_QPSK20M_Right Cheek_Ch132072_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, -	CHEEK, 0.00	Band 66	LTE-FDD, -	1720.000, 132072	8.31	1.35	39.0

Hardware Setup

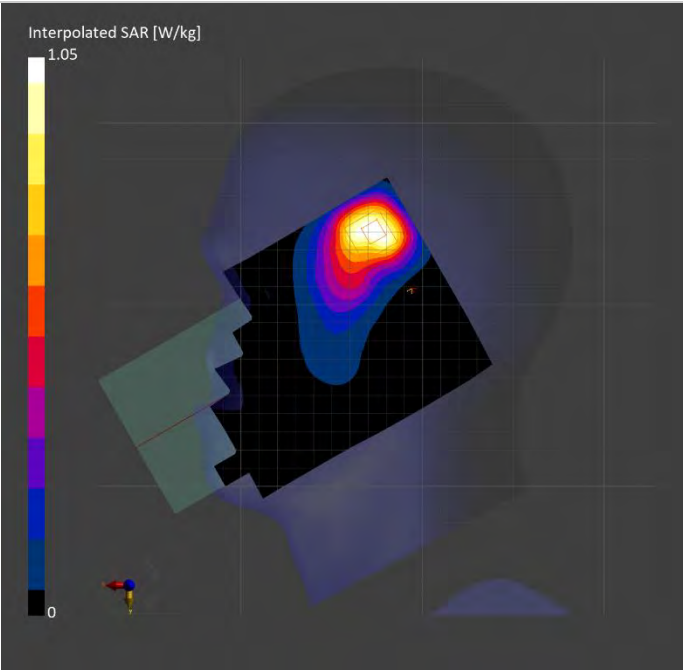
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL1750-2025-04-23	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-23	2025-04-23
psSAR1g [W/kg]	0.864	0.927
psSAR10g [W/kg]	0.507	0.516
Power Drift [dB]	0.02	-0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.5
Dist 3dB Peak [mm]		11.2



P15 LTE B71_QPSK20M_Left Cheek_Ch133222_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, -	CHEEK, 0.00	Band 71	LTE-FDD, -	673.000, 133222	9.87	0.877	43.4

Hardware Setup

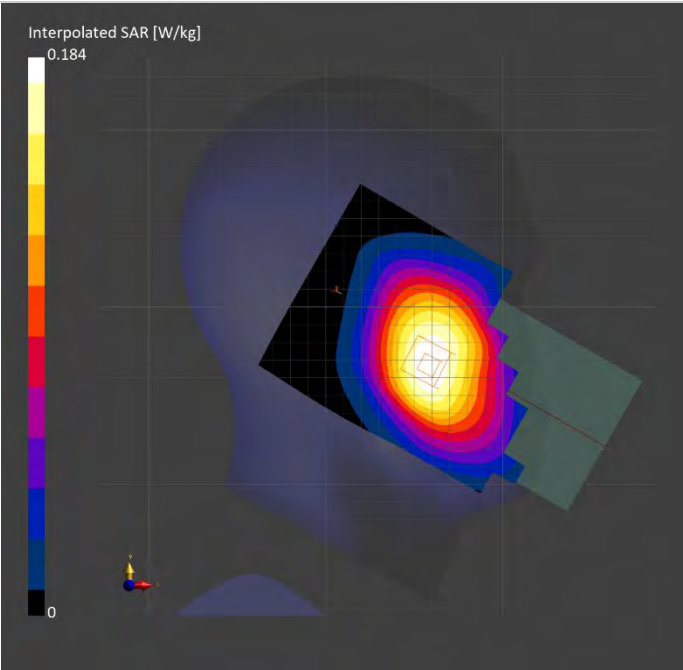
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL750-2025-04-07	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-07	2025-04-07
psSAR1g [W/kg]	0.162	0.170
psSAR10g [W/kg]	0.115	0.135
Power Drift [dB]	-0.09	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		95.4
Dist 3dB Peak [mm]		> 15.0



P16 FR n5_DFT-QPSK20M_Right Cheek_Ch167800_1RB_OS1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, -	CHEEK, 0.00	Band n5	5G NR FR1 FDD, -	839.000, 167800	9.47	0.910	40.6

Hardware Setup

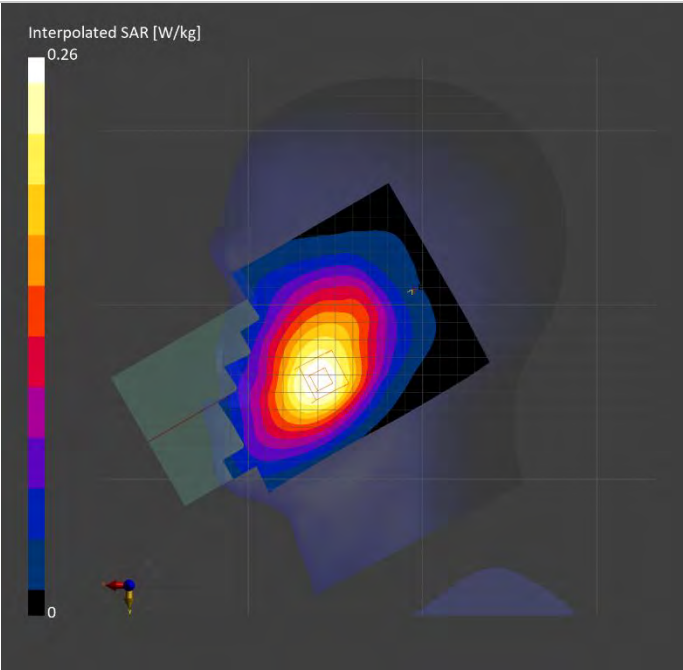
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL835-2025-04-12	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-12	2025-04-12
psSAR1g [W/kg]	0.228	0.237
psSAR10g [W/kg]	0.156	0.184
Power Drift [dB]	-0.08	0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		91.5
Dist 3dB Peak [mm]		> 15.0



P17 FR n7_DFT-QPSK20M_Left Cheek_Ch502000_1RB_OS1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, -	CHEEK, 0.00	Band n7	5G NR FR1 FDD, -	2510.000, 502000	7.31	1.89	38.5

Hardware Setup

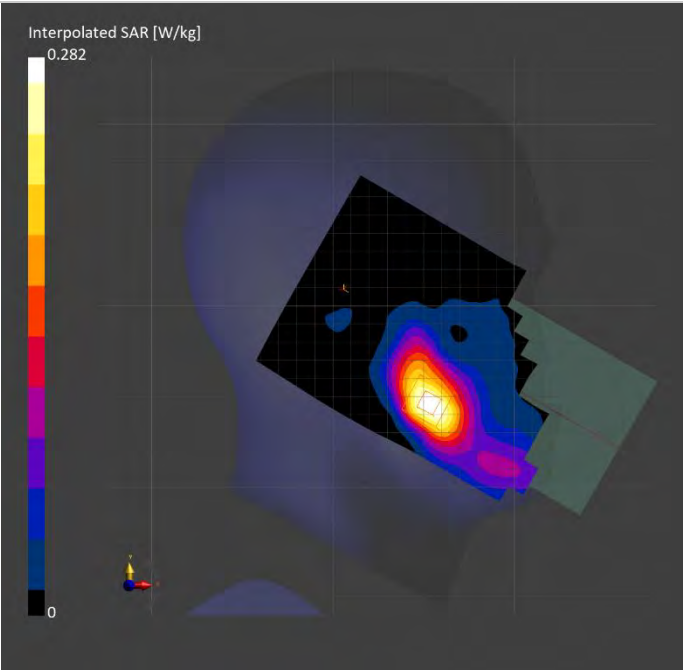
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL2550-2025-05-10	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 220.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-10	2025-05-10
psSAR1g [W/kg]	0.225	0.226
psSAR10g [W/kg]	0.119	0.128
Power Drift [dB]	-0.13	-0.05
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		87.3
Dist 3dB Peak [mm]		12.6



P18 FR n12_DFT-QPSK15M_Right Cheek_Ch141500_1RB_OS1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, -	CHEEK, 0.00	Band n12	5G NR FR1 FDD, -	707.500, 141500	9.87	0.895	43.5

Hardware Setup

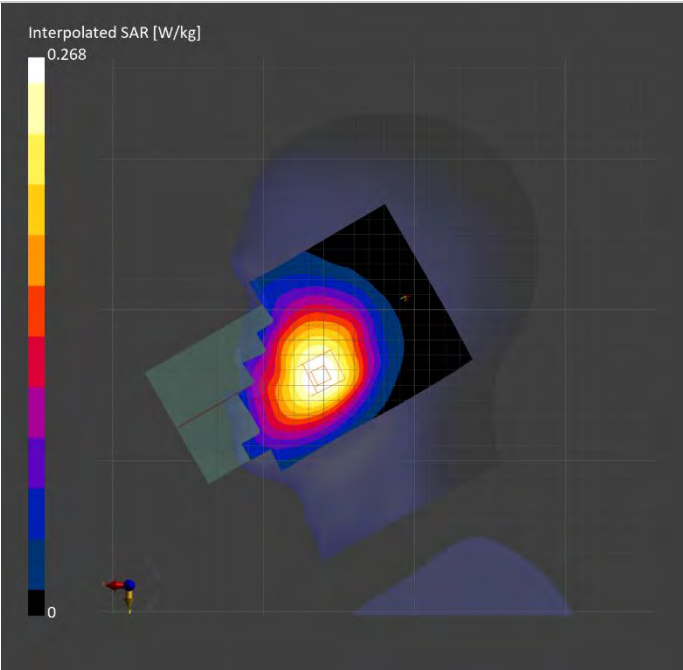
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL750-2025-04-09	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-09	2025-04-09
psSAR1g [W/kg]	0.237	0.208
psSAR10g [W/kg]	0.167	0.198
Power Drift [dB]	-0.01	0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		91.7
Dist 3dB Peak [mm]		> 15.0



P19 FR n13_DFT-QPSK10M_Right Cheek_Ch156400_1RB_OS1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, -	CHEEK, 0.00	Band n13	5G NR FR1 FDD, -	782.000, 156400	9.87	0.920	43.3

Hardware Setup

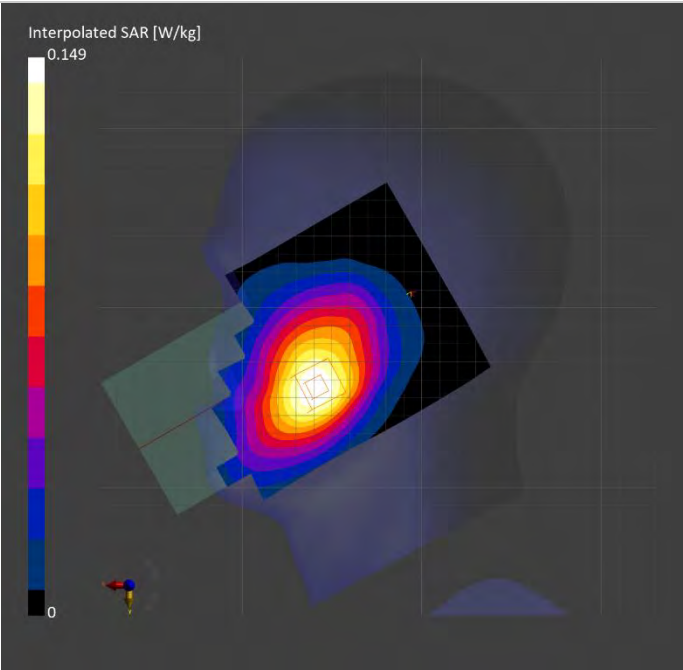
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL750-2025-04-09	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-09	2025-04-09
psSAR1g [W/kg]	0.130	0.135
psSAR10g [W/kg]	0.090	0.106
Power Drift [dB]	-0.10	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		91.6
Dist 3dB Peak [mm]		> 15.0



P20 FR n14_DFT-QPSK10M_Right Cheek_Ch158600_1RB_OS1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, -	CHEEK, 0.00	Band n14	5G NR FR1 FDD, -	793.000, 158600	9.87	0.924	43.3

Hardware Setup

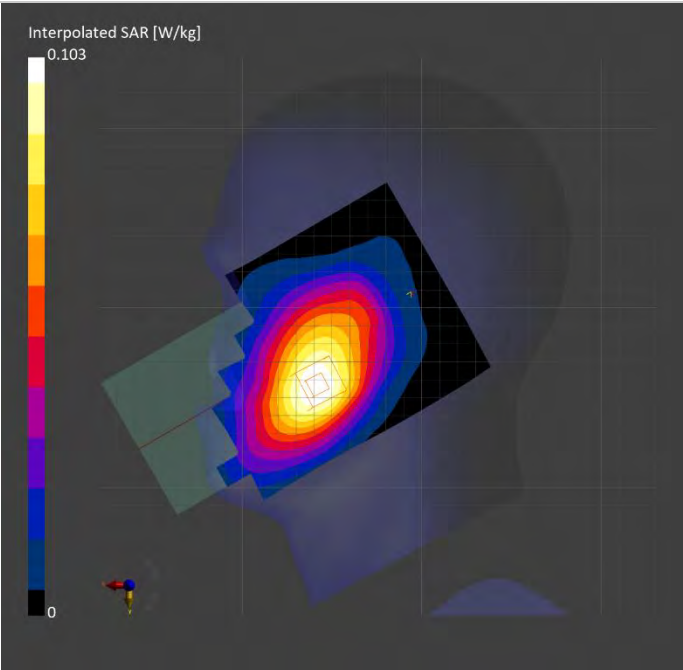
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL750-2025-04-09	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-09	2025-04-09
psSAR1g [W/kg]	0.091	0.094
psSAR10g [W/kg]	0.063	0.074
Power Drift [dB]	-0.05	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		92.9
Dist 3dB Peak [mm]		> 15.0



P21 FR n25_DFT-QPSK20M_Right Cheek_Ch372000_1RB_OS1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, -	CHEEK, 0.00	Band n25	5G NR FR1 FDD, -	1860.000, 372000	7.97	1.35	38.4

Hardware Setup

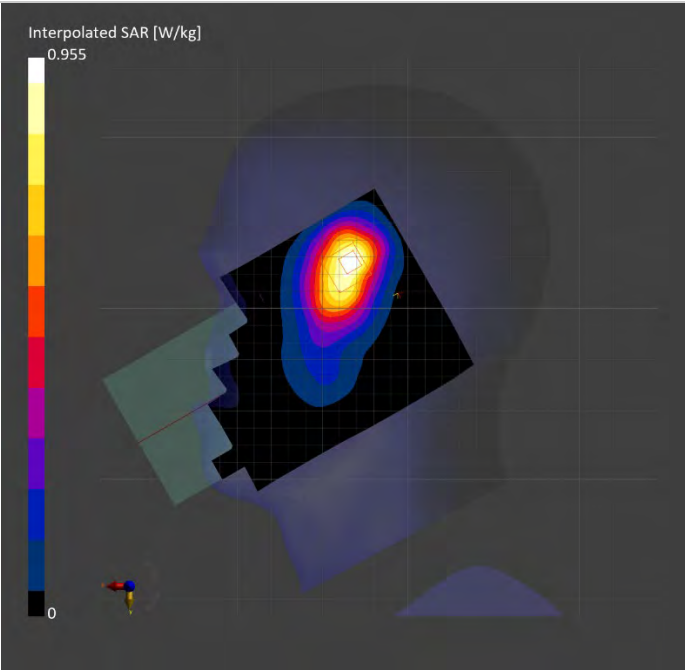
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL1950-2025-05-04	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-04	2025-05-04
psSAR1g [W/kg]	0.768	0.794
psSAR10g [W/kg]	0.446	0.464
Power Drift [dB]	0.02	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		84.9
Dist 3dB Peak [mm]		13.5



P22 FR n30_DFT-QPSK10M_Left Cheek_Ch462000_1RB_OS1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, -	CHEEK, 0.00	Band n30	5G NR FR1 FDD, -	2310.000, 462000	7.71	1.67	38.2

Hardware Setup

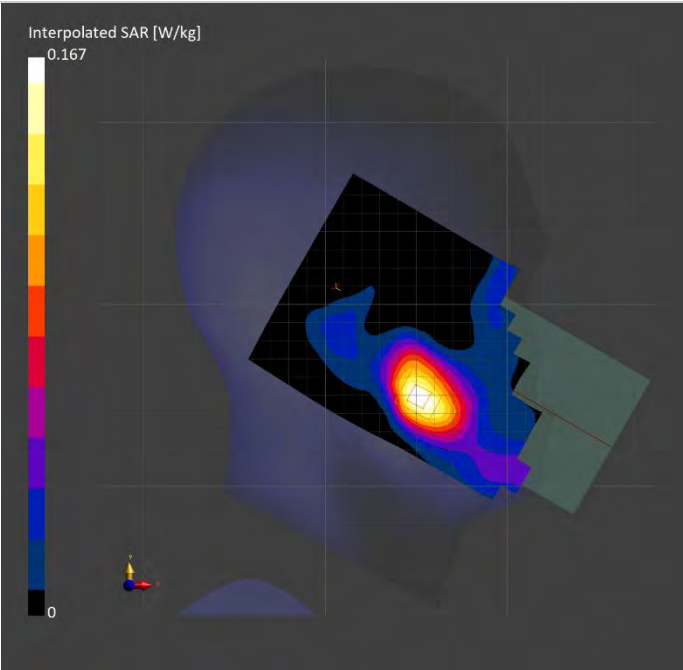
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL2300-2025-04-15	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 220.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-15	2025-04-15
psSAR1g [W/kg]	0.133	0.132
psSAR10g [W/kg]	0.072	0.077
Power Drift [dB]	-0.17	-0.11
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		88.7
Dist 3dB Peak [mm]		12.1



P23 FR n38_DFT-QPSK40M_Left Cheek_Ch518000_50RB_OS28

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, -	CHEEK, 0.00	Band n38	5G NR FR1 TDD, -	2590.000, 518000	7.31	2.00	38.2

Hardware Setup

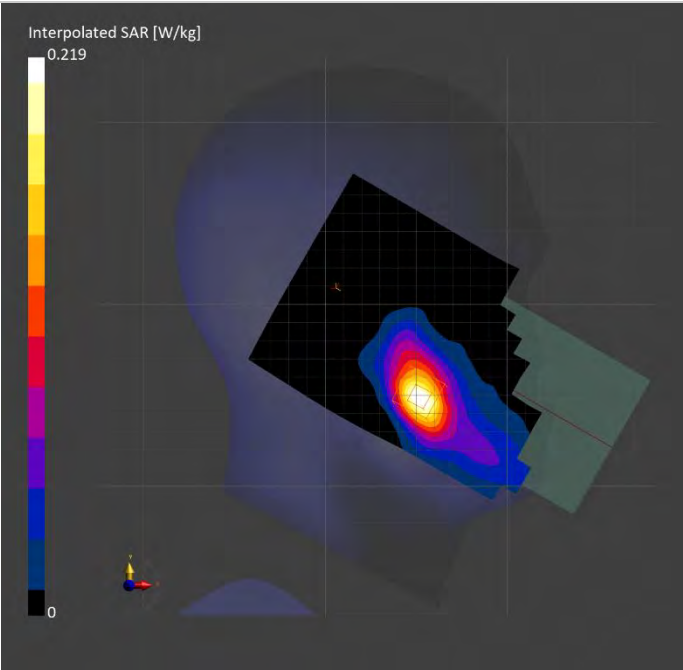
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL2550-2025-04-17	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 220.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-17	2025-04-17
psSAR1g [W/kg]	0.169	0.272
psSAR10g [W/kg]	0.084	0.090
Power Drift [dB]	0.01	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		84.3
Dist 3dB Peak [mm]		11.2



P24 FR n41_DFT-QPSK100M_Right Cheek_Ch528000_1RB_OS1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, -	CHEEK, 0.00	Band n41	5G NR FR1 TDD, -	2640.000, 528000	7.31	1.96	37.7

Hardware Setup

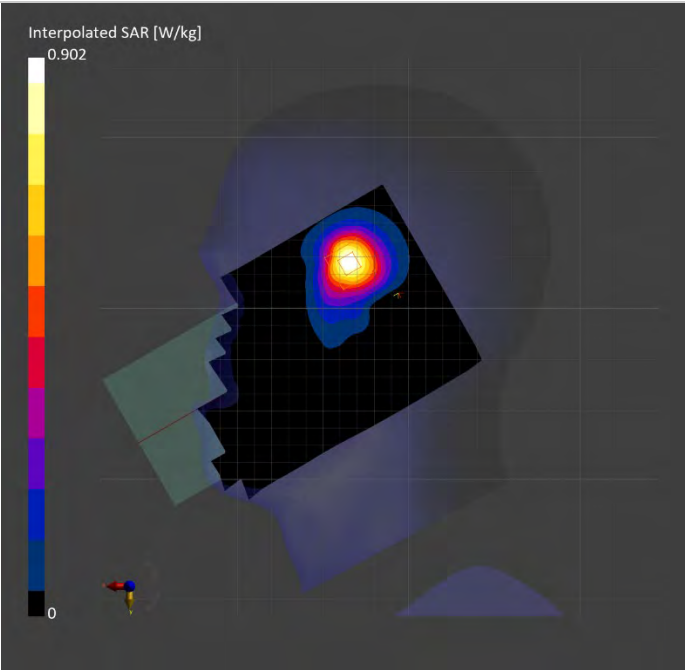
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL2550-2025-04-21	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 220.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-21	2025-04-21
psSAR1g [W/kg]	0.699	0.750
psSAR10g [W/kg]	0.346	0.382
Power Drift [dB]	-0.06	0.17
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.3
Dist 3dB Peak [mm]		11.5



P25 FR n48_DFT-QPSK40M_Right Cheek_Ch645332_1RB_OS1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, -	CHEEK, 0.00	Band n48	5G NR FR1 TDD, -	3679.98, 645332	6.50	2.95	37.5

Hardware Setup

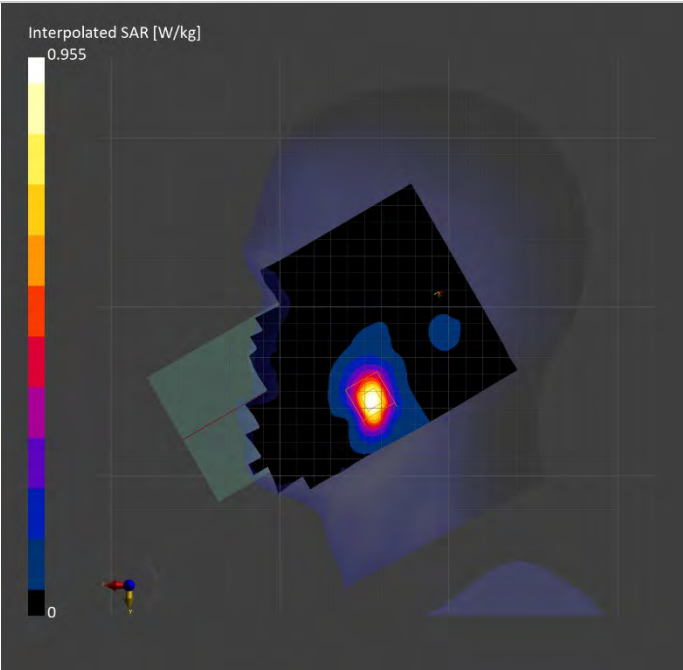
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL3700-2025-05-14	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	128.0 x 208.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	8.0 x 8.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-14	2025-05-14
psSAR1g [W/kg]	0.683	0.698
psSAR10g [W/kg]	0.272	0.307
Power Drift [dB]	-0.22	0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		76.9
Dist 3dB Peak [mm]		8.2



P26 FR n66_DFT-QPSK30M_Right Cheek_Ch349000_160RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, -	CHEEK, 0.00	Band n66	5G NR FR1 FDD, -	1745.000, 349000	8.31	1.43	38.3

Hardware Setup

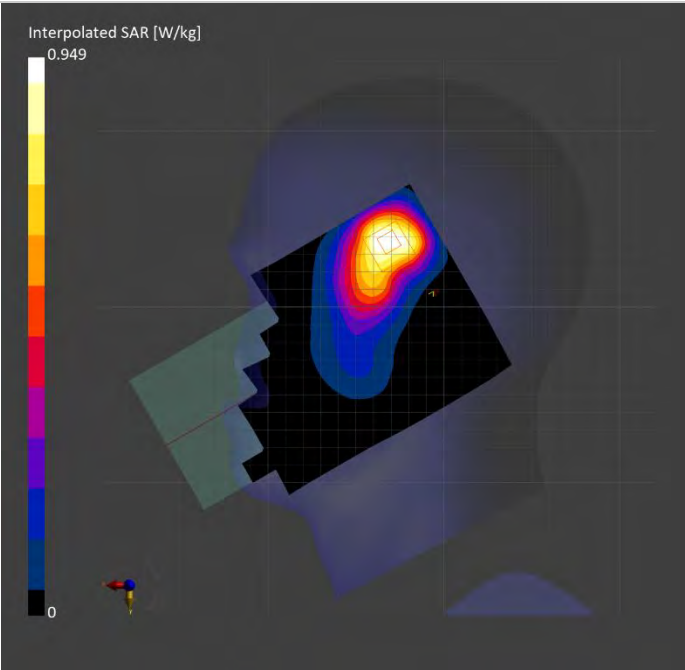
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL1750-2025-04-26	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-26	2025-04-26
psSAR1g [W/kg]	0.786	0.681
psSAR10g [W/kg]	0.471	0.389
Power Drift [dB]	-0.02	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		82.1
Dist 3dB Peak [mm]		12.0



P27 FR n71_DFT-QPSK20M_Right Cheek_Ch136100_1RB_OS1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, -	CHEEK, 0.00	Band n71	5G NR FR1 FDD, -	652.000, 136100	9.87	0.875	43.8

Hardware Setup

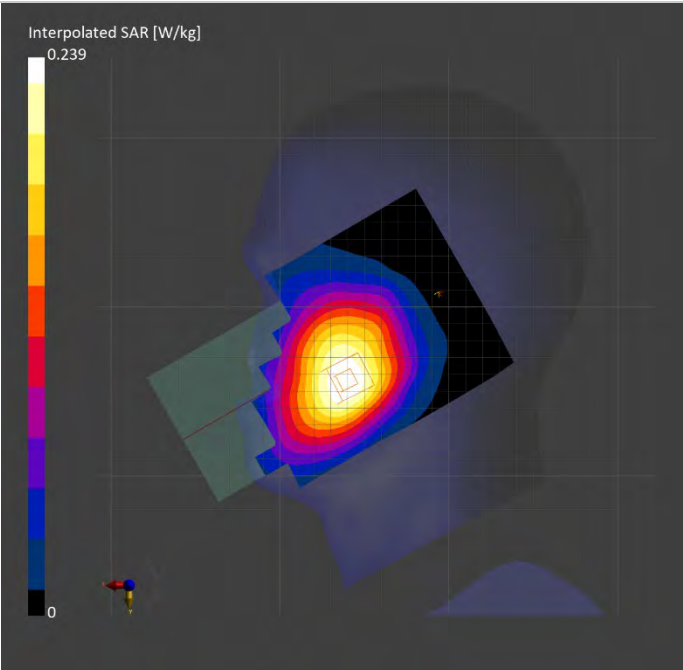
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL750-2025-04-07	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-07	2025-04-07
psSAR1g [W/kg]	0.212	0.231
psSAR10g [W/kg]	0.149	0.167
Power Drift [dB]	-0.11	0.15
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		91.1
Dist 3dB Peak [mm]		> 15.0



P28 FR n77_DFT-QPSK100M_Right Cheek_Ch662000_135RB_OS69

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, -	CHEEK, 0.00	Band n77	5G NR FR1 TDD, -	3930.000, 662000	6.40	3.17	37.1

Hardware Setup

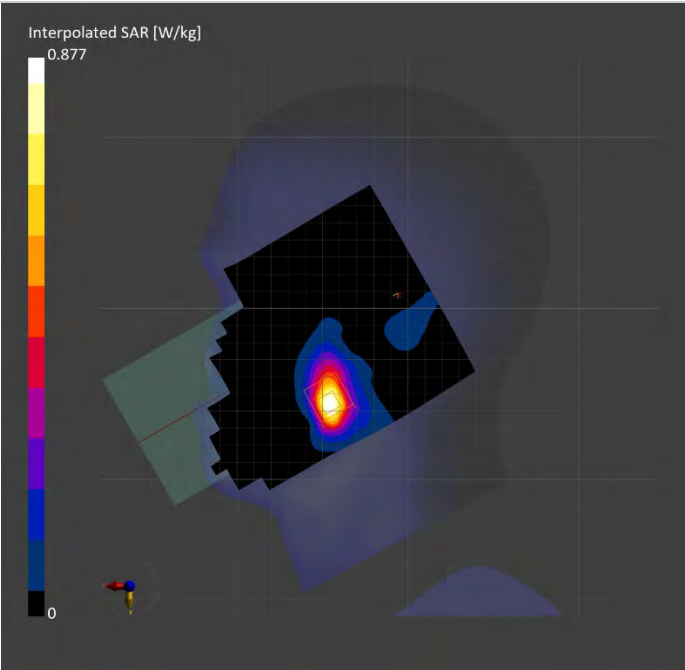
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL3900-2025-05-16	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	128.0 x 208.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	8.0 x 8.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-16	2025-05-16
psSAR1g [W/kg]	0.621	0.630
psSAR10g [W/kg]	0.243	0.249
Power Drift [dB]	0.02	-0.12
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		75.7
Dist 3dB Peak [mm]		9.2



P29 WLAN 2.4G_802.11g_Right Cheek_Ch1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, -	CHEEK, 0.00	WLAN 2.4GHz	WLAN, -	2412.000, 1	7.46	1.80	39.3

Hardware Setup

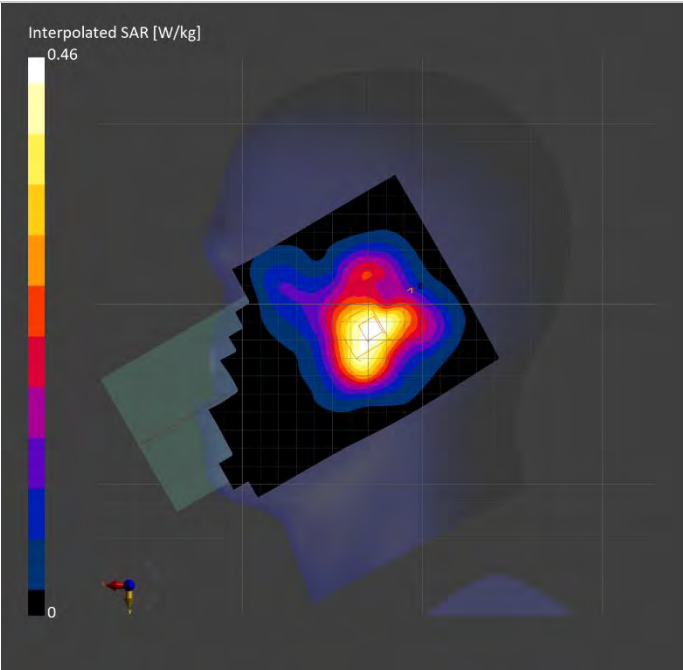
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL2450-2025-04-11	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 220.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-11	2025-04-11
psSAR1g [W/kg]	0.368	0.376
psSAR10g [W/kg]	0.208	0.218
Power Drift [dB]	-0.14	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		82.5
Dist 3dB Peak [mm]		12.8



P30 WLAN 5G_802.11n_Left Cheek_Ch64

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, -	CHEEK, 0.00	WLAN 5GHz	WLAN, -	5320.000, 64	5.16	4.65	35.4

Hardware Setup

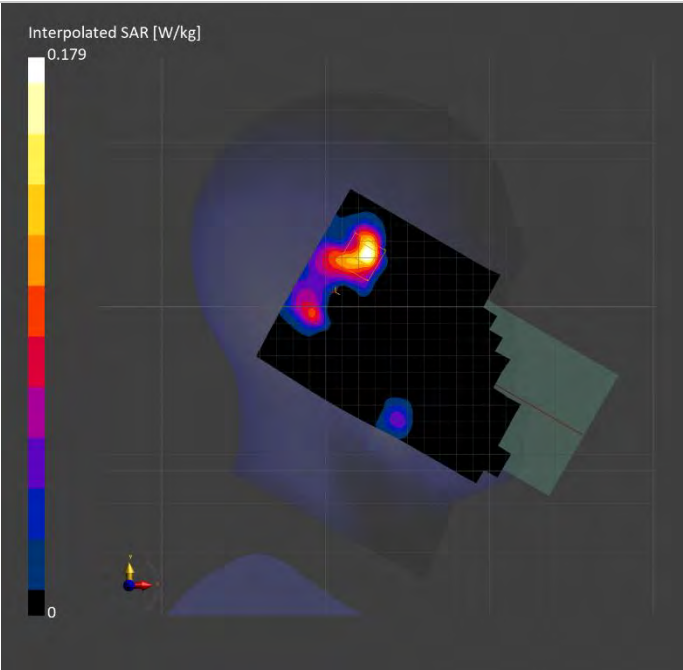
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL5G-2025-05-20	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 220.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-20	2025-05-20
psSAR1g [W/kg]	0.092	0.094
psSAR10g [W/kg]	0.020	0.023
Power Drift [dB]	0.04	-0.06
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		64.3
Dist 3dB Peak [mm]		5.4



P31 WLAN 5G_802.11n_Left Cheek_Ch134

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, -	CHEEK, 0.00	WLAN 5GHz	WLAN, -	5670.000, 134	4.56	5.05	34.8

Hardware Setup

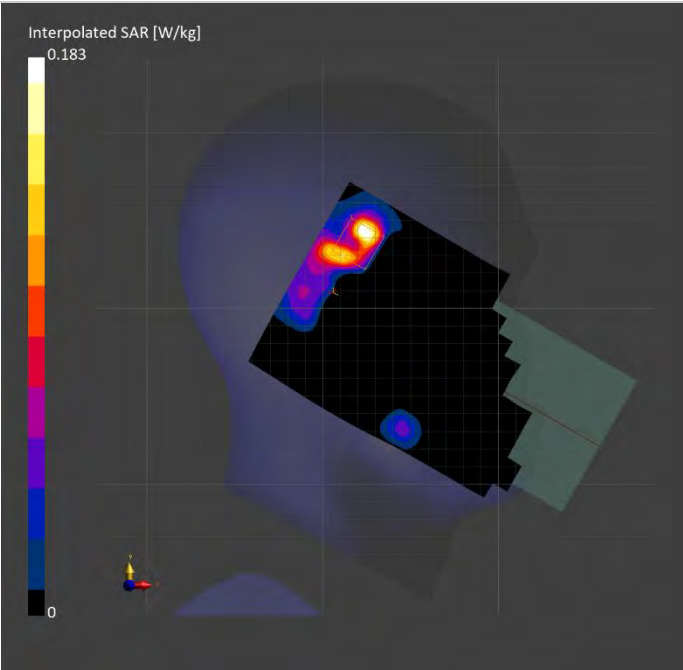
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL5G-2025-05-21	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 220.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-21	2025-05-21
psSAR1g [W/kg]	0.116	0.129
psSAR10g [W/kg]	0.039	0.033
Power Drift [dB]	-0.08	0.05
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		66.5
Dist 3dB Peak [mm]		5.8



P32 WLAN 5G_802.11a_Right Tilted_CH157

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	TILT, 0.00	WLAN 5GHz	WLAN,	5785.000, 157	4.62	5.20	34.4

Hardware Setup

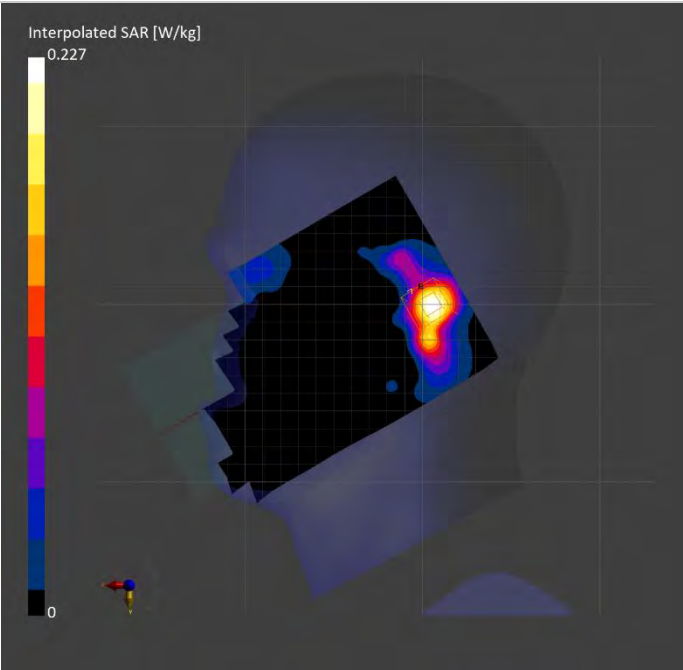
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL5G-2025-05-22	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 220.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-22	2025-05-22
psSAR1g [W/kg]	0.166	0.123
psSAR10g [W/kg]	0.063	0.058
Power Drift [dB]	-0.03	-0.07
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		59.5
Dist 3dB Peak [mm]		8.9



P33 BT_GFSK_Left Cheek_Ch39

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, -	CHEEK, 0.00	ISM 2.4 GHz Band	Bluetooth, -	2441.000, 39	7.46	1.82	39.3

Hardware Setup

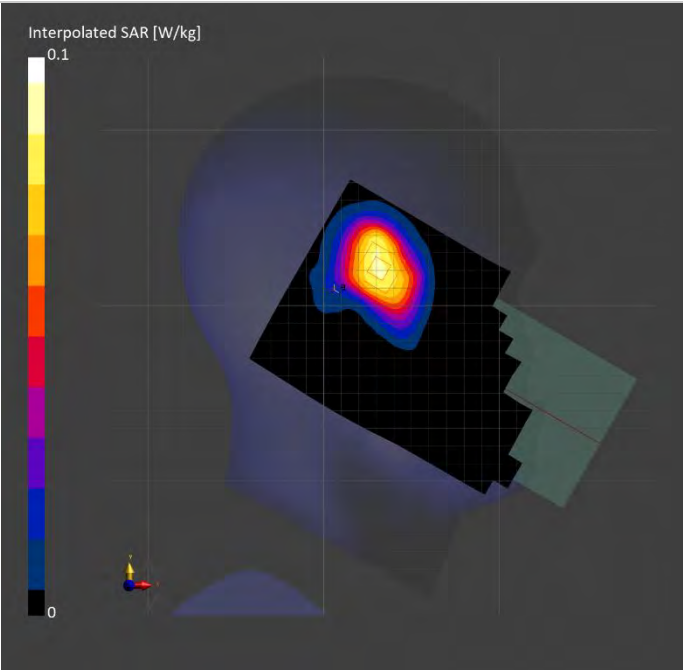
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL2450-2025-04-11	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 220.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-11	2025-04-11
psSAR1g [W/kg]	0.070	0.028
psSAR10g [W/kg]	0.040	0.017
Power Drift [dB]	0.02	-0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		78.1
Dist 3dB Peak [mm]		10.6



P34 LTE B5_QPSK10M_Rear Face_1cm_Ch20600_1RB_OS49

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 10.00	Band 5	LTE-FDD, -	844.000, 20600	9.47	0.912	40.6

Hardware Setup

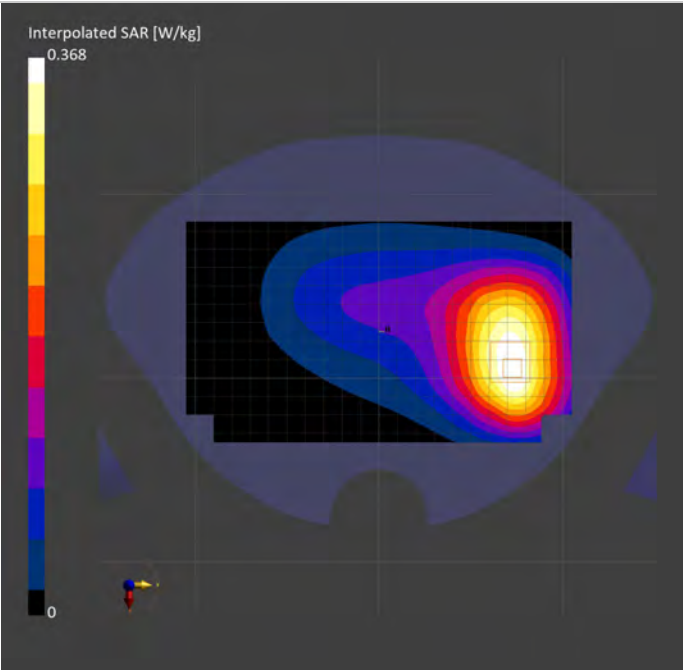
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSSL835-2025-04-12	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-12	2025-04-12
psSAR1g [W/kg]	0.324	0.321
psSAR10g [W/kg]	0.222	0.195
Power Drift [dB]	0.02	-0.05
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.7
Dist 3dB Peak [mm]		> 15.0



P35 LTE B7_QPSK20M_Rear Face_1cm_Ch20850_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 10.00	Band 7	LTE-FDD, -	2510.000, 20850	7.31	1.85	39.1

Hardware Setup

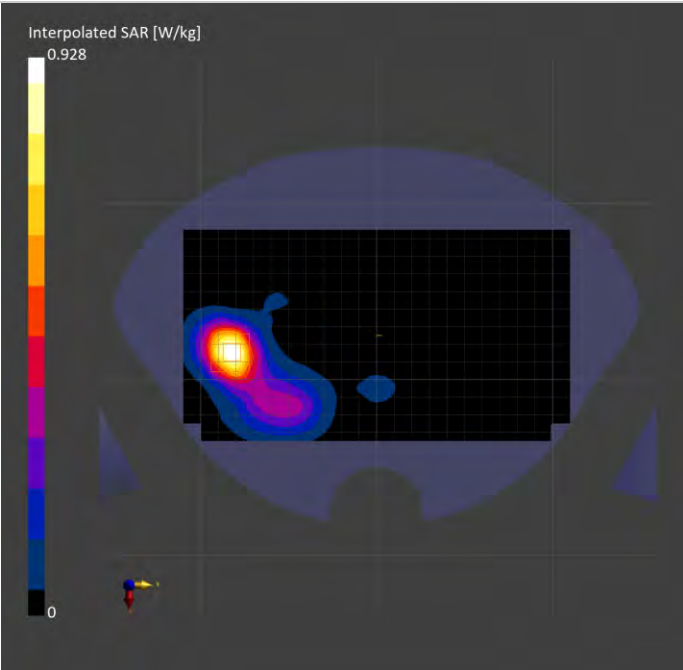
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL2550-2025-05-08	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 220.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-08	2025-05-08
psSAR1g [W/kg]	0.725	0.749
psSAR10g [W/kg]	0.354	0.371
Power Drift [dB]	0.02	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		82.4
Dist 3dB Peak [mm]		12.1



P36 LTE B12_QPSK10M_Rear Face_1cm_Ch23095_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 10.00	Band 12	LTE-FDD, -	707.500, 23095	9.87	0.895	43.5

Hardware Setup

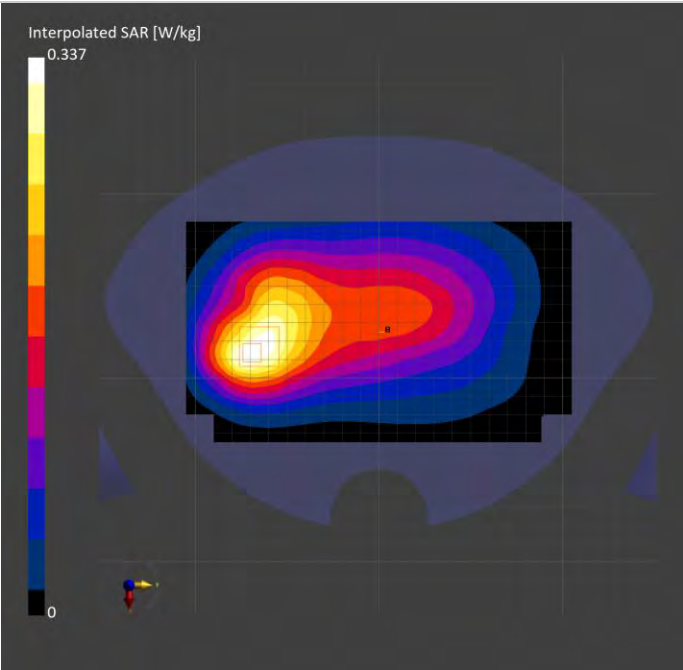
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2162	HSL750-2025-04-08	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-08	2025-04-08
psSAR1g [W/kg]	0.292	0.345
psSAR10g [W/kg]	0.200	0.223
Power Drift [dB]	-0.00	0.11
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		82.2
Dist 3dB Peak [mm]		16.7



P37 LTE B13_QPSK10M_Rear Face_1cm_Ch23230_1RB_OS24

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 10.00	Band 13	LTE-FDD, -	782.000, 23230	9.06	0.920	43.3

Hardware Setup

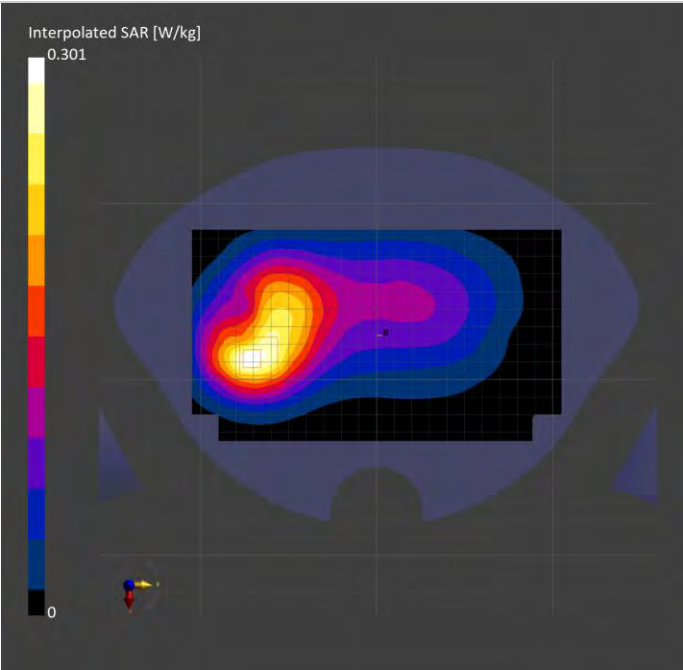
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2162	HSL750-2025-04-08	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-08	2025-04-08
psSAR1g [W/kg]	0.255	0.254
psSAR10g [W/kg]	0.167	0.156
Power Drift [dB]	-0.01	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		81.8
Dist 3dB Peak [mm]		15.2



P38 LTE B14_QPSK10M_Rear Face_1cm_CH23330_25RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 10.00	Band 14	LTE-FDD, -	793.000, 23330	9.87	0.924	43.3

Hardware Setup

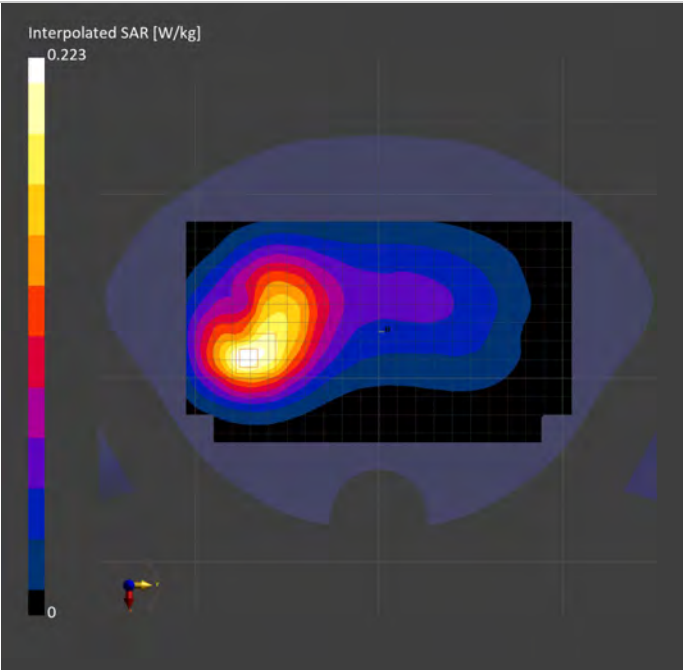
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2162	HSL750-2025-04-08	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-08	2025-04-08
psSAR1g [W/kg]	0.188	0.189
psSAR10g [W/kg]	0.123	0.116
Power Drift [dB]	-0.01	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		84.2
Dist 3dB Peak [mm]		14.9



P39 LTE B25_QPSK20M_Rear Face_1cm_Ch26140_1RB_OS50

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 10.00	Band 25	LTE-FDD, -	1860.000, 26140	7.97	1.46	40.4

Hardware Setup

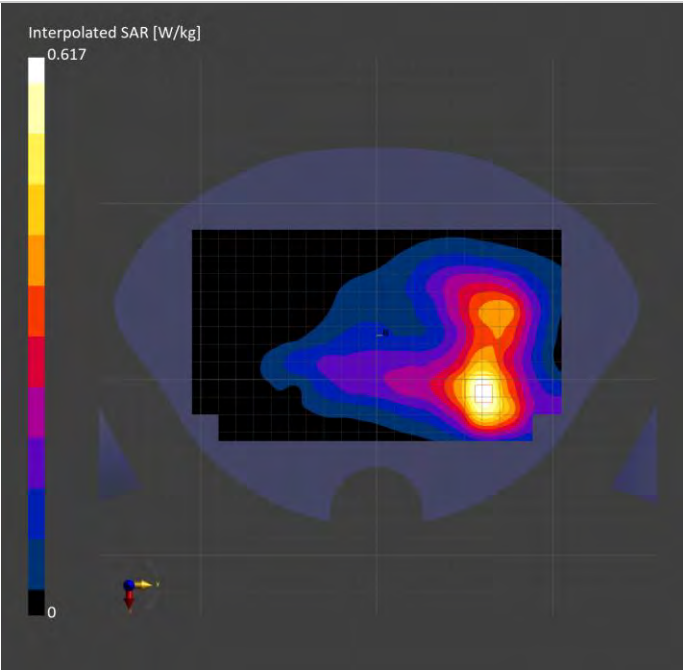
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL1950-2025-04-30	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-30	2025-04-30
psSAR1g [W/kg]	0.507	0.536
psSAR10g [W/kg]	0.292	0.299
Power Drift [dB]	-0.04	-0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		82.5
Dist 3dB Peak [mm]		12.8



P40 LTE B26_QPSK15M_Rear Face_1cm_Ch26765_1RB_OS74

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 10.00	Band 26	LTE-FDD, -	821.500, 26765	9.47	0.895	43.0

Hardware Setup

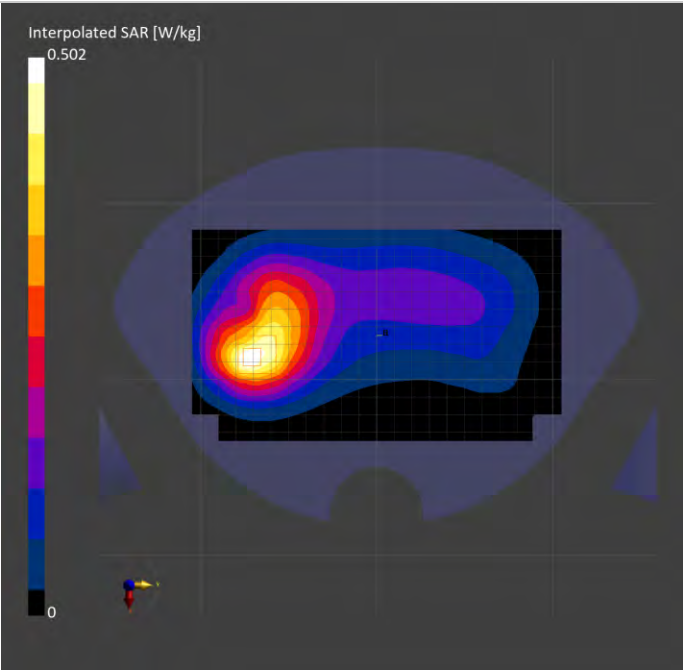
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL835-2025-04-13	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-13	2025-04-13
psSAR1g [W/kg]	0.426	0.430
psSAR10g [W/kg]	0.277	0.262
Power Drift [dB]	-0.01	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.8
Dist 3dB Peak [mm]		14.1



P41 LTE B30_QPSK10M_Rear Face_1cm_Ch27710_1RB_OS24

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 10.00	Band 30	LTE-FDD, -	2310.000, 27710	7.71	1.74	40.4

Hardware Setup

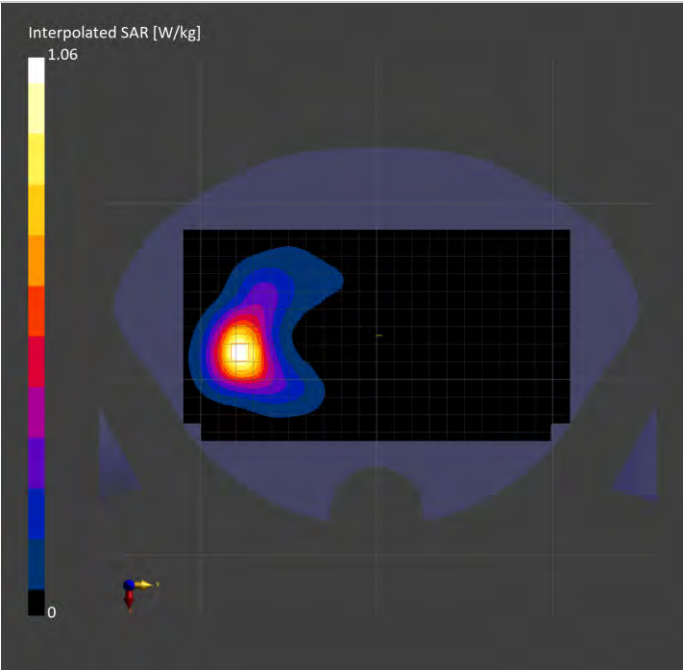
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL2300-2025-04-14	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 220.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-14	2025-04-14
psSAR1g [W/kg]	0.831	0.857
psSAR10g [W/kg]	0.427	0.435
Power Drift [dB]	0.00	-0.14
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		82.7
Dist 3dB Peak [mm]		12.7



P42 LTE B38_QPSK20M_Rear Face_1cm_Ch37850_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 10.00	Band 38	LTE-TDD, -	2580.000, 37850	7.31	1.92	40.1

Hardware Setup

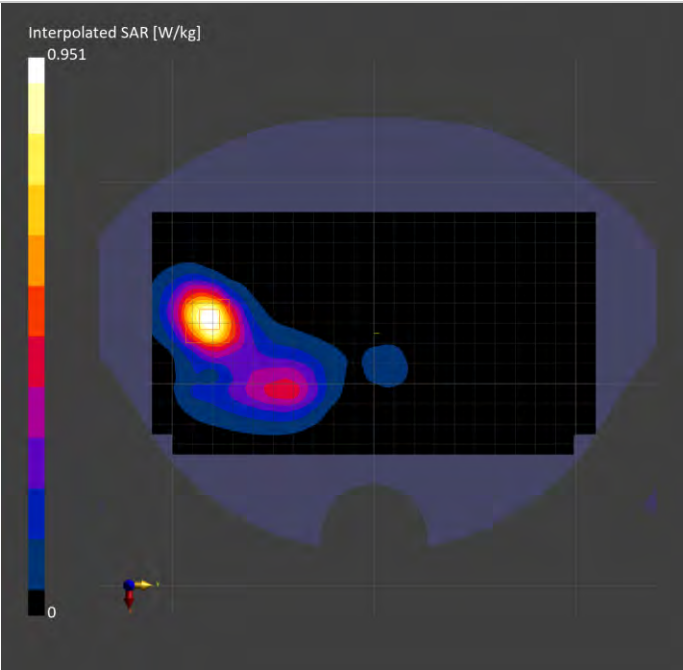
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL2550-2025-04-16	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 220.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-16	2025-04-16
psSAR1g [W/kg]	0.742	0.761
psSAR10g [W/kg]	0.355	0.364
Power Drift [dB]	-0.01	0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		81.0
Dist 3dB Peak [mm]		11.4



P43 LTE B41_QPSK20M_Rear Face_1cm_Ch39750_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 10.00	Band 41	LTE-TDD, -	2506.000, 39750	7.46	1.91	39.0

Hardware Setup

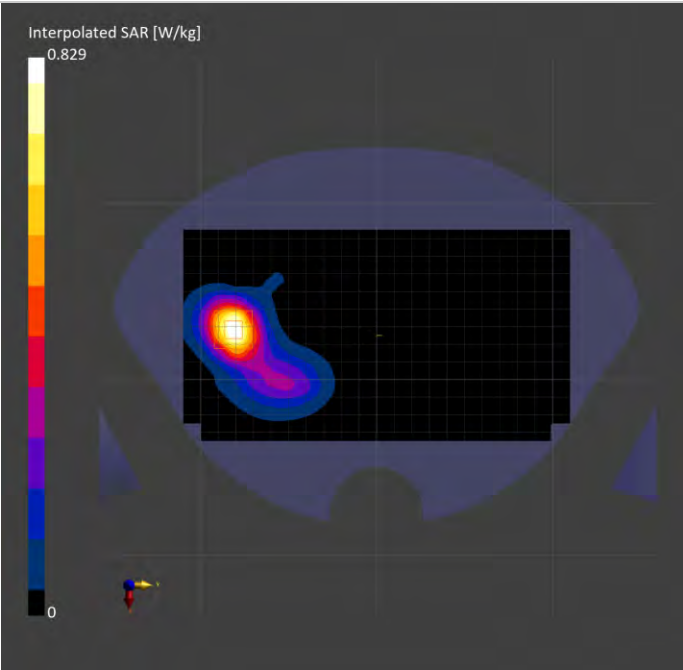
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL2550-2025-04-19	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 220.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-19	2025-04-19
psSAR1g [W/kg]	0.652	0.668
psSAR10g [W/kg]	0.318	0.327
Power Drift [dB]	0.03	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		81.7
Dist 3dB Peak [mm]		11.8



P44 LTE B42_QPSK20M_Rear Face_1cm_Ch42190_50RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 10.00	Band 42	LTE-TDD, -	3460.000, 42190	6.71	2.88	39.2

Hardware Setup

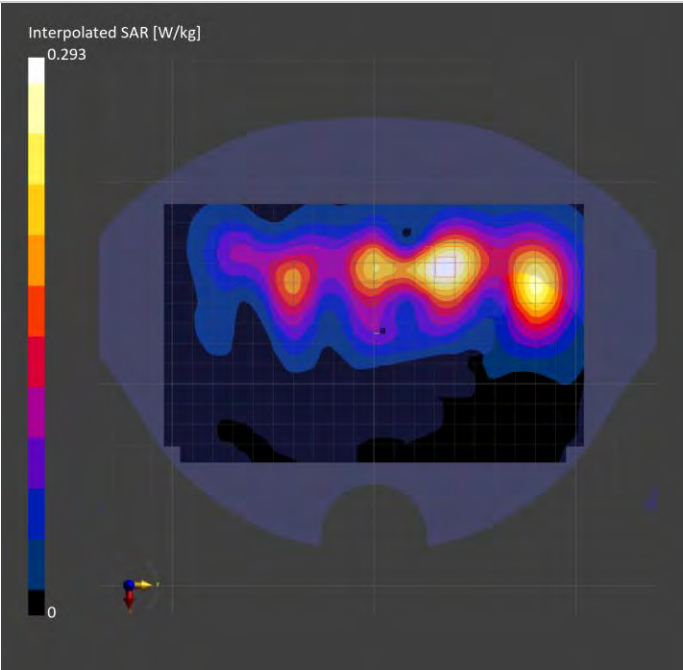
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL3500-2025-05-11	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	128.0 x 208.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	8.0 x 8.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-11	2025-05-11
psSAR1g [W/kg]	0.225	0.310
psSAR10g [W/kg]	0.108	0.144
Power Drift [dB]	0.05	0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		76.0
Dist 3dB Peak [mm]		13.7



P45 LTE B43_QPSK20M_Rear Face_1cm_Ch44490_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 10.00	Band 43	LTE-TDD, -	3690.000, 44490	6.50	3.03	37.4

Hardware Setup

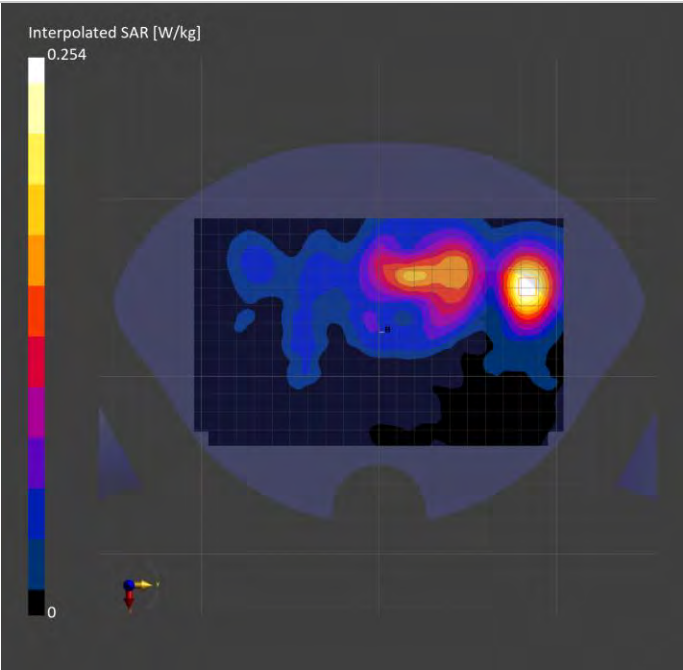
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL3700-2025-05-12	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	128.0 x 208.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	8.0 x 8.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-12	2025-05-12
psSAR1g [W/kg]	0.191	0.347
psSAR10g [W/kg]	0.086	0.163
Power Drift [dB]	0.03	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		75.9
Dist 3dB Peak [mm]		12.2



P46 LTE B48_QPSK20M_Rear Face_1cm_Ch56640_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 10.00	Band 48	LTE-TDD, -	3690.000, 56640	6.50	3.05	37.5

Hardware Setup

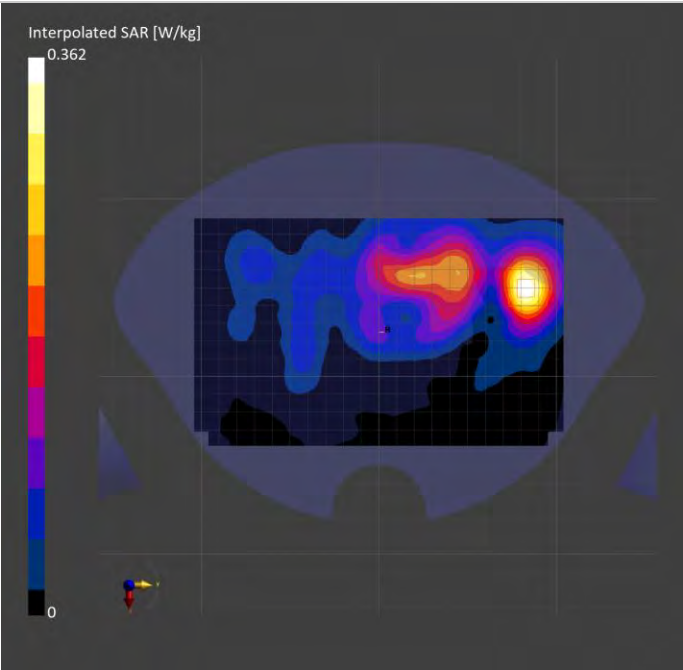
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL3700-2025-05-13	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	128.0 x 208.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	8.0 x 8.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-13	2025-05-13
psSAR1g [W/kg]	0.272	0.313
psSAR10g [W/kg]	0.123	0.155
Power Drift [dB]	-0.01	0.13
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		76.8
Dist 3dB Peak [mm]		12.4



P47 LTE B66_QPSK20M_Rear Face_1cm_Ch132072_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 87.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 10.00	Band 66	LTE-FDD, -	1720.000, 132072	8.31	1.35	39.0

Hardware Setup

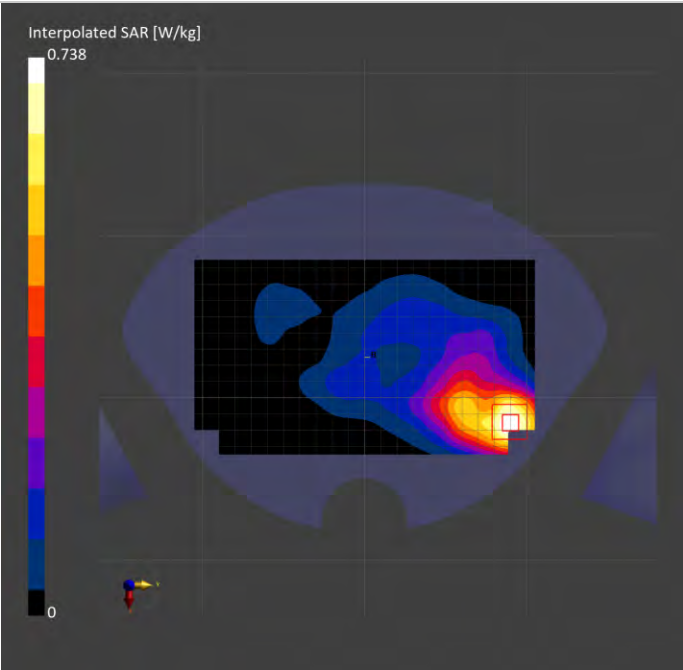
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL1750-2025-04-24	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-24	2025-04-24
psSAR1g [W/kg]	0.610	0.565
psSAR10g [W/kg]	0.364	0.327
Power Drift [dB]	-0.26	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.0
Dist 3dB Peak [mm]		20.4



P48 LTE B71_QPSK20M_Rear Face_1cm_Ch133222_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 10.00	Band 71	LTE-FDD, -	673.000, 133222	9.87	0.853	43.9

Hardware Setup

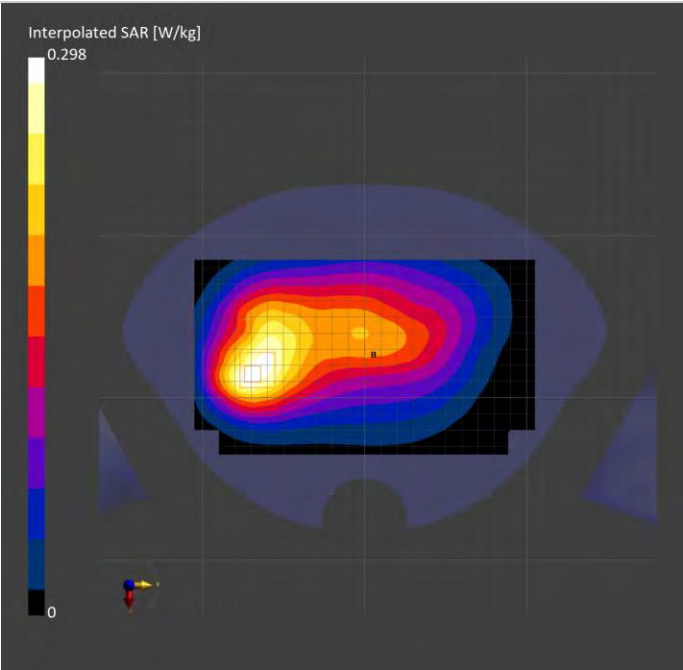
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL750-2025-04-08	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-08	2025-04-08
psSAR1g [W/kg]	0.258	0.259
psSAR10g [W/kg]	0.178	0.161
Power Drift [dB]	-0.00	-0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		81.5
Dist 3dB Peak [mm]		16.1



P49 FR n5_DFT-QPSK20M_Rear Face_1cm_Ch167800_50RB_OS28

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 10.00	Band n5	5G NR FR1 FDD, -	839.000, 167800	9.47	0.910	40.6

Hardware Setup

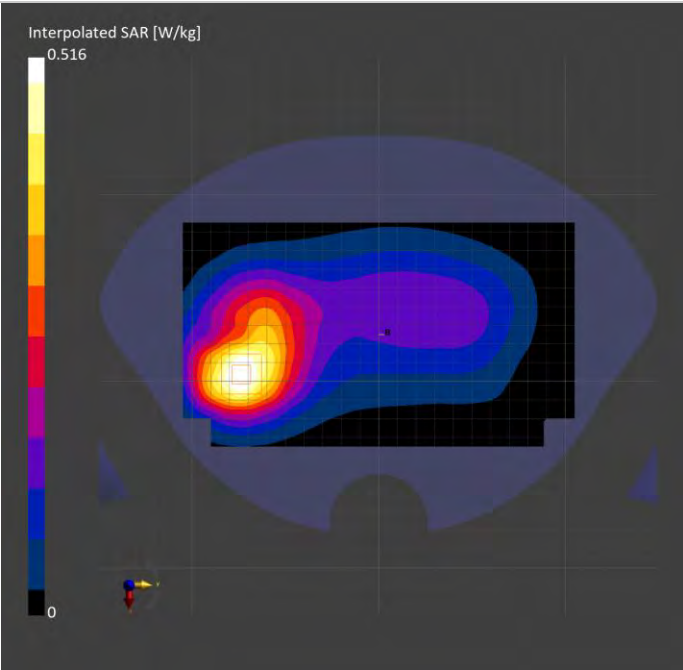
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL835-2025-04-12	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-12	2025-04-12
psSAR1g [W/kg]	0.454	0.474
psSAR10g [W/kg]	0.302	0.293
Power Drift [dB]	0.09	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		82.8
Dist 3dB Peak [mm]		14.1



P50 FR n7_DFT-QPSK20M_Rear Face_1cm_Ch507000_1RB_OS1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	178.0 x 86.0 x 17.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 10.00	Band n7	5G NR FR1 FDD, -	2535.000, 507000	7.31	1.91	38.4

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL2550-2025-05-10	EX3DV4-SN3873,2024-09-29	DAE4 Sn1389,2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 220.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-10	2025-05-10
psSAR1g [W/kg]	0.632	0.624
psSAR10g [W/kg]	0.316	0.312
Power Drift [dB]	-0.37	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		82.4
Dist 3dB Peak [mm]		12.8

